

2011/2012  
NETZSCH North America  
Training Academy On Tour

March 6-7, 2012  
University of California  
at Davis

## NETZSCH Simultaneous TGA-DSC & Evolved Gas Analysis Instruments User Meeting

This two day user meeting is designed to provide an opportunity to get the latest information on new developments



# NETZSCH North America Training Academy On Tour

# NETZSCH

## Content

This two day user meeting is designed to provide an opportunity for NETZSCH STA-FTIR, -MS, and -GC-MS users to come together, get the latest information on new developments, share ideas, and build their network of connections within this specialized field.

Participants are encouraged to present brief talks about one or more problems, solutions, and/or successes they have experienced. These presentations are not designed to be "polished" talks, just an opportunity for discussion in a friendly and supportive environment.

## Target group

NETZSCH STA-FTIR, -MS, and -GC-MS users

### Lecturers

Experts from NETZSCH

### Location

University of California at Davis

### Participation fee

Registration Fee: \$140

Discounts are available for multiple attendees from the same organization. Contact NETZSCH for more information. Please note that seating is limited.

Should you have any further questions, please do not hesitate to contact

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We are looking forward to meeting you!

You can conveniently register online  
[www.netsch.com/NIBonTour](http://www.netsch.com/NIBonTour)

## Day 1

- 09:00 am Welcome
- 09:20 am STA Basics: New Platform Instruments, Accessories
- 09:45 am TG, DSC Theory
- 10:30 am BREAK
- 10:50 am Optimization of measurement parameters, influence of measurement parameters on TG and DSC results
- 12:15 am LUNCH
- 01:00 pm Temperature, Sensitivity Calibration,  $C_p$  measurements
- 01:45 pm Invited Lecture
- 02:30 pm News from Hardware and Software: 2400°C furnace, high speed furnace
- 03:00 pm Workshop: Routine maintenance and troubleshooting, sample preparation, software questions, evaluation and interpretation of customer measurements
- 04:00 pm Lab visit (all)

## Day 2

- 09:00 am Introduction: Instruments and couplings
- 09:30 am Coupling techniques: Basics, Solutions, Applications
- 10:30 am BREAK
- 10:50 am Invited Lecture
- 11:10 am Invited Lecture
- 11:30 am Software News
- 12:00 am LUNCH
- 01:00 pm Tips and tricks: Optimization of MS results
- 01:45 pm Working with NIST data base
- 02:15 pm Hardware news: TG-GC-MS coupling, STA-SPI (single photo ionization)-MS
- 02:45 pm BREAK
- 03:00 pm Workshop: Troubleshooting MS hardware, customer measurement files evaluation and interpretation